

Notice of References Cited	Application/Control No. 12/799,945		Applicant(s)/Patent Under Reexamination CHAGANTI ET AL.	
	Examiner BENJAMIN E. LANIER		Art Unit 2432	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,832,208 A	11-1998	Chen et al.	726/24
*	B	US-6,405,195 B1	06-2002	Ahlberg, Christopher	709/219
*	C	US-2002/0069272 A1	06-2002	Kim et al.	709/221
*	D	US-6,507,865 B1	01-2003	Hanson et al.	705/36R
*	E	US-2004/0021686 A1	02-2004	Barberis, Romain P.	345/738
*	F	US-6,792,458 B1	09-2004	Muret et al.	709/224
*	G	US-6,882,793 B1	04-2005	Fu et al.	386/241
*	H	US-7,155,737 B1	12-2006	Lim et al.	726/2
*	I	US-7,167,904 B1	01-2007	Devarajan et al.	709/218
*	J	US-7,353,199 B1	04-2008	DiStefano, III, Thomas L.	705/37
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	X				

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